

L Number	Hits	Search Text	DB	Time stamp
1	1	5523694.pn.	USPAT; US-PGPUB	2004/04/27 10:46
2	1	5523694.pn. and (induc\$6 with (failure\$2 or defect\$2))	USPAT; US-PGPUB	2004/04/27 10:54
3	161	((electron near2 beam) with (inspect\$5 near4 semiconductor)	USPAT; US-PGPUB	2004/04/27 10:51
4	4	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and (induc\$6 with (failure\$2 or defect\$2))	USPAT; US-PGPUB	2004/04/27 10:53
5	0	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and ((maximum adj rating) with (failure\$2 or defect\$2))	USPAT; US-PGPUB	2004/04/27 10:53
6	0	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and (until with (failure\$2 near3 induc\$3))	USPAT; US-PGPUB	2004/04/27 10:55
7	0	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and (failure\$2 near3 induced)	USPAT; US-PGPUB	2004/04/27 10:56
8	1	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and ((failure\$2 or damage\$2) near3 induced)	USPAT; US-PGPUB	2004/04/27 10:57
9	0	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and (live near3 test\$5)	USPAT; US-PGPUB	2004/04/27 10:58
10	5	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and (operation\$4 near3 test\$5)	USPAT; US-PGPUB	2004/04/27 11:01
11	5	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and ((operation\$4 or durability) near3 test\$5)	USPAT; US-PGPUB	2004/04/27 11:02
12	1	((electron near2 beam) with (inspect\$5 near4 semiconductor)) and (durability near3 test\$5)	USPAT; US-PGPUB	2004/04/27 11:02